



Notice of References Cited

Application/Control No.

10/664,631

Applicant(s)/Patent Under
Reexamination
ERAN ET AL.

Examiner

TUAN H. NGUYEN

Art Unit

2618

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0203740	10-2004	Won et al.	455/426.1
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	I	US-			
	J	US-			
	K	US-			
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FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

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FORM PTO-1449 (Colb)	ATTY DOCKET NO. 91366	SERIAL NUMBER 10/764,963
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS' INFORMATION STATEMENT	APPLICANT Eran SHPAK	EXAMINER (N/A)
	FILING DATE January 26, 2004	GROUP ART UNIT 3679



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Examiner's Initials		DOCUMENT NO.	DATE	NAME	CLASS	SUB	FILING DATE
	AA	2004/0203740	10-2004	Won, et al.			
	AB						
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